

<b>Notice of References Cited</b>	Application/Control No. 10/600,767	Applicant(s)/Patent Under Reexamination NAKAYAMA, TOMOHIRO	
	Examiner Viet Q Nguyen	Art Unit 2818	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-5,485,595	01-1996	Assar et al.	711/103
	B	US-5,907,856	05-1999	Estakhri et al.	711/103
	C	US-5,563,828	10-1996	Hasbun et al.	365/185.33
	D	US-6,772,274	08-2004	Estakhri, Petro	711/103
	E	US-5,309,393	05-1994	Sakata et al.	365/189.01
	F	US-5,907,856	05-1999	Estakhri et al.	711/103
	G	US-5,838,614	11-1998	Estakhri et al.	365/185.11
	H	US-6,223,308	04-2001	Estakhri et al.	714/42
	I	US-		<b>VIET Q. NGUYEN PRIMARY EXAMINER</b>	
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP2002016232	01-2002	Japan	Kato et al	H01I 27/05
	O	JP02001118391A	04-2001	Japan	Kimura	G11C 16/02
	P	JP409045091A	02-1997	Japan	Matsuda	G11C 16/06
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	<b>VIET Q. NGUYEN PRIMARY EXAMINER</b>
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.